Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/009,579	DE LEIJ ET AL.	
Examiner	Art Unit	_
Colina V. Oian Bh D	1636	

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
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SEARCH (INCLUDING SEAF	NOTES RCH STRATEGY	
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